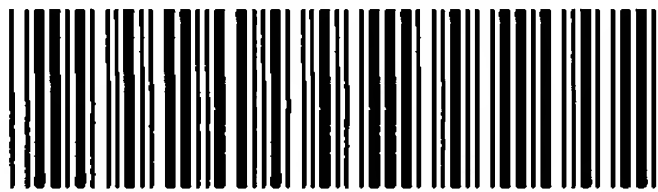


Search Notes



Application/Control No.

10/617,172

Examiner

Tianjie Chen

Applicant(s)/Patent under Reexamination

KIM ET AL.

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
Updated		10/10/2007	TJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR